IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of:

Tomoyuki ISHII et al.

Appln. No.:

Group Art Unit:

Filed: HEREWITH

For: SEMICONDUCTOR MEMORY DEVICE

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to 37 C.F.R. § 1.56, and without any assertion as to materiality or prior art effect, the documents listed on the attached Form PTO-1449 are hereby cited.

The documents on the attached List were cited in the specification, on pages 2-3, and their relevance is indicated therein.

Respectfully submitted,

MWS:lat

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October 15, 2003

Bv:

Mitchell W. Shapiro

Reg. No. 31,568

FORM PTO-1449					Atty. Docket No.		App]	Appln. No.	
					XA-9945	· ·			
LIST	OF.	DOCUMENTS C	TED BY A						
					Applicant				
					Tomoyuki ISHII et al.				
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	AQ Kobayashi, et al., "A Giga-Scale Assist-Gate (AG) - (AND) - Type Flash Memory Cell with 20-MB/s Programming Throughput for Content-Downloading Applications," IEEE International Electron Devices Meeting 2001 pp. 29-32.								
-	AR Eitan, et al., "Can NROM, a 2 Bit, Trapping Storage NVM Cell, Give a Real Challenge to Floating Gate Cells?" International Conference on Solid State Devices and Materials 1999, pp. 522-524.								
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